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Examiner	_

Yogesh K. Aggarwal

Applicant(s)/Patent under Reexamination
HONMA, YOSHIHIRO
Art Unit
2615

SEARCHED				
Subclass	Date	Examiner		
	(X)			
		Subclass Date		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH I (INCLUDING SEAR	CH STRATEG	Y)
	DATE	EXMR
used the same reference	6/20/2005	YKA
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